



RADIO TEST REPORT

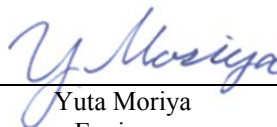
Test Report No. : 11182619H-D-R1

Applicant : silex technology, Inc.
Type of Equipment : SDIO Wireless Module
Model No. : SX-SDMAC
FCC ID : N6C-SDMAC
Test regulation : FCC Part 15 Subpart E: 2016
(DFS test only)
Test Result : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
6. This test report covers Radio technical requirements. It does not cover administrative issues such as Manual or non-Radio test related Requirements. (if applicable)
7. This report is a revised version of 11182619H-D. 11182619H-D is replaced with this report.

Date of test: August 30 and 31, 2016

Representative test engineer:


Yuta Moriya
Engineer

Consumer Technology Division

Approved by:



Tsubasa Takayama
Engineer

Consumer Technology Division



NVLAP LAB CODE: 200572-0

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*As for the range of Accreditation in NVLAP, you may refer to the WEB address,
http://japan.ul.com/resources/emc_accredited/

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SECTION 1: Customer information

Company Name : silex technology, Inc.
Address : 2-3-1 Hikaridai, Seika-cho, Kyoto 619-0237, Japan
Telephone Number : +81-774-98-3878
Facsimile Number : +81-774-98-3758
Contact Person : Toshiro Kometani

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : SDIO Wireless Module
Model No. : SX-SDMAC
Serial No. : Refer to Section 4, Clause 4.2
Rating : DC 3.3 V
Receipt Date of Sample : March 7, 2016
Country of Manufacture : Japan
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

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2.2 Product Description

Model: SX-SDMAC (referred to as the EUT in this report) is a SDIO Wireless Module.

General Specification

Clock frequency(ies) in the system : 48 MHz
Operating Temperature : -40 deg. C - +85 deg. C

Radio Specification

Radio Type : Transceiver
Method of Frequency Generation : Synthesizer
Power Supply (inner) : DC 1.1 V

	IEEE802.11b	IEEE802.11g/n (20 M band)	IEEE802.11a/n/ac (20 M band)	IEEE802.11n/ac (40 M band)	IEEE802.11ac (80 M band)	Bluetooth Ver.4.0 with EDR function
Frequency of operation	2412 MHz - 2462 MHz	2412 MHz - 2462 MHz	2412 MHz - 2462 MHz 5180 MHz - 5240 MHz 5260 MHz - 5320 MHz *1) 5500 MHz - 5700 MHz *1) 5745 MHz - 5825 MHz	2422 MHz - 2452 MHz 5190 MHz - 5230 MHz 5270 MHz - 5310 MHz *1) 5510 MHz - 5670 MHz *1) 5755 MHz - 5795 MHz	5210 MHz 5290 MHz *1) 5530 MHz - 5610 MHz *1) 5775 MHz	2402 MHz - 2480 MHz
Type of modulation	DSSS (CCK, DQPSK, DBPSK)	OFDM-CCK (64QAM, 16QAM, QPSK, BPSK)	11a/n: OFDM (64QAM, 16QAM, QPSK, BPSK) 11ac: OFDM (64QAM, 16QAM, QPSK, BPSK, 256QAM)			BT: FHSS (GFSK, $\pi/4$ -DQPSK, 8-DPSK) LE: GFSK
Channel spacing	5 MHz		20 MHz	40 MHz	80 MHz	BT: 1 MHz LE: 2 MHz
Antenna type	[Antenna 1] Model Name: 146153 PCB antenna (Dipole antenna) [Antenna 2] Model Name: H2U84W1H1S Chip Antenna					
Antenna Connector type	Antenna 1: U.FL Alternative connectorUFL Antenna 2: -none					
Antenna Gain	Antenna 1: 3.25 dBi (2.4 GHz Band), 5.0 dBi (5 GHz Band) Antenna 2: 1.40 dBi (2.4 GHz Band), 2.3 dBi (5 GHz Band)					

*1) This test report applies to IEEE802.11a / n-20 / n-40 / ac-20 / ac-40 / ac-80 (W53, W56 band).

* Spurious emission test was performed with two antenna type (PCB antenna (Dipole antenna) and Chip antenna).

** WLAN and Bluetooth do not transmit simultaneously.

SECTION 3: Scope of Report

This report only covers DFS requirement, as specified by the following referenced procedures.

SECTION 4: Test specification, procedures & results

4.1 Test Specification

Test Specification	:	FCC Part 15 Subpart E: 2016, final revised on April 6, 2016
Title	:	FCC 47CFR Part15 Radio Frequency Device Subpart E Unlicensed National Information Infrastructure Devices Section 15.407 General technical requirements
Test Specification	:	KDB905462 D02 UNII DFS Compliance Procedures New Rules v02
Title	:	COMPLIANCE MEASUREMENT PROCEDURES FOR UNLICENSED- NATIONAL INFORMATION INFRASTRUCTURE DEVICES OPERATING IN THE 5250-5350MHz AND 5470-5725MHz BANDS INCORPORATING DYNAMIC FREQUENCY SELECTION
Test Specification	:	KDB905462 D03 Client Without DFS New Rules v01r02
Title	:	U-NII CLIENT DEVICES WITHOUT RADAR DETECTION CAPABILITY

FCC Part 15.31 (e)

The stable voltage (DC1.1V) was provided to the EUT during the tests.
Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

[PCB antenna (Dipole antenna)]

The EUT has a unique coupling/antenna connector (UFL). Therefore the equipment complies with the requirement of 15.203.

[Chip Antenna]

The antenna is not removable from the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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4.2 Procedures and results

Table 1: Applicability of DFS Requirements

Requirement	Operating Mode	Test Procedures & Limits	Deviation	Results
	Client without Radar Detection			
U-NII Detection Bandwidth	Not required	KDB905462 D02 UNII DFS Compliance Procedures New Rules v02	N/A	N/A
Initial Channel Availability Check Time	Not required	FCC15.407 (h)	N/A	N/A
		KDB905462 D02 UNII DFS Compliance Procedures New Rules v02		
		RSS-247 6.3		
Radar Burst at the Beginning of the Channel Availability Check Time	Not required	FCC15.407 (h)	N/A	N/A
		KDB905462 D02 UNII DFS Compliance Procedures New Rules v02		
		RSS-247 6.3		
Radar Burst at the End of the Channel Availability Check Time	Not required	FCC15.407 (h)	N/A	N/A
		KDB905462 D02 UNII DFS Compliance Procedures New Rules v02		
		RSS-247 6.3		
In-Service Monitoring for Channel Move Time, Channel Closing Transmission Time	Yes	FCC15.407 (h)	N/A	Complied
		KDB905462 D02 UNII DFS Compliance Procedures New Rules v02		
		RSS-247 6.3		
In-Service Monitoring for Non-Occupancy period	Yes *	FCC15.407 (h)	N/A	Complied
		KDB905462 D02 UNII DFS Compliance Procedures New Rules v02		
		RSS-247 6.3		
Statistical Performance Check	Not required	FCC15.407 (h)	N/A	N/A
		KDB905462 D02 UNII DFS Compliance Procedures New Rules v02		
Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0422.				

*Although this test was not required in FCC, KDB 905462 D02, it was performed as additional test.

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Table 2 DFS Detection Thresholds for Master Devices and Client Devices With Radar Detection

Maximum Transmit Power	Value (See Notes 1,2, and 3)
≥ 200 milliwatt	-64 dBm
< 200 milliwatt and power spectral density < 10dBm/MHz	-62 dBm
< 200 milliwatt that do not meet the power spectral density requirement	-64 dBm
Note 1: This is the level at the input of the receiver assuming a 0 dBi receive antenna. Note 2: Throughout these test procedures an additional 1 dB has been added to the amplitude of the test transmission waveforms to account for variations in measurement equipment. This will ensure that the test signal is at or above the detection threshold level to trigger a DFS response. Note 3: EIRP is based on the highest antenna gain. For MIMO devices refer to KDB Publication 662911 D01.	

Table 3 DFS Response Requirement Values

Parameter	Value
Non-occupancy period	Minimum 30 minutes
Channel Availability Check Time	60 seconds
Channel Move Time	10 seconds See Note 1
Channel Closing Transmission Time	200 milliseconds + an aggregate of 60 milliseconds over remaining 10 second period. See Notes 1 and 2
U-NII Detection Bandwidth	Minimum 100 % of the U-NII 99 % transmission power bandwidth See Note 3
Note 1: Channel Move Time and the Channel Closing Transmission Time should be performed with Radar Type 0. The measurement timing begins at the end of the Radar Type 0 burst. Note 2: The Channel Closing Transmission Time is comprised of 200 milliseconds starting at the beginning of the Channel Move Time plus any additional intermittent control signals required to facilitate a Channel move (an aggregate of 60 milliseconds) during the remainder of the 10 second period. The aggregate duration of control signal will not count quiet periods in between transmissions. Note 3: During the U-NII Detection Bandwidth detection test, radar type 0 should be used. For each frequency step the minimum percentage of detection is 90 percent. Measurements are performed with no data traffic.	

Table 4 Short Pulse Radar Test Waveform

Radar Type	Pulse Width (μsec)	PRI (μsec)	Number of Pulses	Minimum Percentage of Successful Detection	Minimum Number of Trials
0	1	1428	18	See Note 1	See Note 1
1	1	Test A: 15 unique PRI values randomly selected from the list of 23 PRI values in Table 5a Test B: 15 unique PRI values randomly selected within the range of 518-3066 μsec, with a minimum increment of 1 μsec, excluding PRI values selected in Test A	Roundup{(1/360)* (19*10 ⁶ /PRI μsec)}	60 %	30
2	1-5	150-230	23-29	60 %	30
3	6-10	200-500	16-18	60 %	30
4	11-20	200-500	12-16	60 %	30
Aggregate (Rader Types 1-4)				80 %	120
Note 1: Short Pulse Radar Type 0 should be used for the detection bandwidth test, channel move time, and channel closing time tests.					

Table 5 Long Pulse Radar Test Waveform

Radar Type	Pulse Width (μsec)	Chip Width (MHz)	PRI (μsec)	Number of Pulses per Burst	Number of Burst	Minimum Percentage of Successful Detection	Minimum Number of Trials
5	50-100	5 - 20	1000-2000	1-3	8-20	80 %	30

Table 6 Frequency Hopping Radar Test Waveform

Radar Type	Pulse Width (μsec)	PRI (μsec)	Pulse per Hop (kHz)	Hopping Rate (kHz)	Hopping Sequence Length (msec)	Minimum Percentage of Successful Detection	Minimum Number of Trials
6	1	333	9	0.333	300	70 %	30

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4.3 Test Location

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Test site	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms	Maximum measurement distance
No.1 semi-anechoic chamber	2973C-1	19.2 x 11.2 x 7.7	7.0 x 6.0	No.1 Power source room	10 m
No.2 semi-anechoic chamber	2973C-2	7.5 x 5.8 x 5.2	4.0 x 4.0	-	3 m
No.3 semi-anechoic chamber	2973C-3	12.0 x 8.5 x 5.9	6.8 x 5.75	No.3 Preparation room	3 m
No.3 shielded room	-	4.0 x 6.0 x 2.7	N/A	-	-
No.4 semi-anechoic chamber	2973C-4	12.0 x 8.5 x 5.9	6.8 x 5.75	No.4 Preparation room	3 m
No.4 shielded room	-	4.0 x 6.0 x 2.7	N/A	-	-
No.5 semi-anechoic chamber	-	6.0 x 6.0 x 3.9	6.0 x 6.0	-	-
No.6 shielded room	-	4.0 x 4.5 x 2.7	4.0 x 4.5	-	-
No.6 measurement room	-	4.75 x 5.4 x 3.0	4.75 x 4.15	-	-
No.7 shielded room	-	4.7 x 7.5 x 2.7	4.7 x 7.5	-	-
No.8 measurement room	-	3.1 x 5.0 x 2.7	N/A	-	-
No.9 measurement room	-	8.8 x 4.6 x 2.8	2.4 x 2.4	-	-
No.11 measurement room	-	6.2 x 4.7 x 3.0	4.8 x 4.6	-	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0 m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

4.4 Uncertainty

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.
Time Measurement uncertainty for this test was: (±) 0.012%

4.5 Test instruments of DFS and Test set up

Refer to APPENDIX.

SECTION 5: Operation of E.U.T. during testing

5.1 Operating Modes

Operation frequencies: Please see page 5.

The channel-loading of approximately 17% or greater was used for testing, and its test data was transferred from the Master Device to the Client Device for all test configurations.

The EUT utilizes the 802.11a/n/ac architecture, with a 20MHz, 40MHz and 80MHz channel bandwidth.

The FCC ID for the Master Device used with EUT for DFS testing is LDK102087.

The rated output power of the Master unit is >200mW(23dBm). Therefore the required interference threshold level is -64 dBm. After correction for antenna gain and procedural adjustments, the required conducted threshold at the antenna port is $-64 + 1 + 0 = -63.0$ dBm (threshold level + additional 1dB + antenna gain).

It is impossible for users to change DFS control, because the DFS function is written on the firmware and users cannot access it.

*DFS test was performed on U.FL port because the structures of the route to both antennas are the same.

The EUT was set by the software as follows:

Software name:iperf

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5.3 Test and Measurement System

SYSTEM OVERVIEW

The measurement system is based on a conducted test method.

The software selects waveform parameters from within the bounds of the signal type on a random basis using uniform distribution. The short pulse types 1, 2, 3, and 4, the long pulse type 5, and the frequency hopping type 6 parameters are randomized at run-time.

The signal monitoring equipment consists of a spectrum analyzer with the capacity to display 8001 bins on the horizontal axis. A time-domain resolution of 2 msec/bin is achievable with a 16 second sweep time, meeting the 10 seconds short pulse reporting criteria. The aggregate ON time is calculated by multiplying the number of bins above a threshold during a particular observation period by the dwell time per bin, with the analyzer set to peak detection.

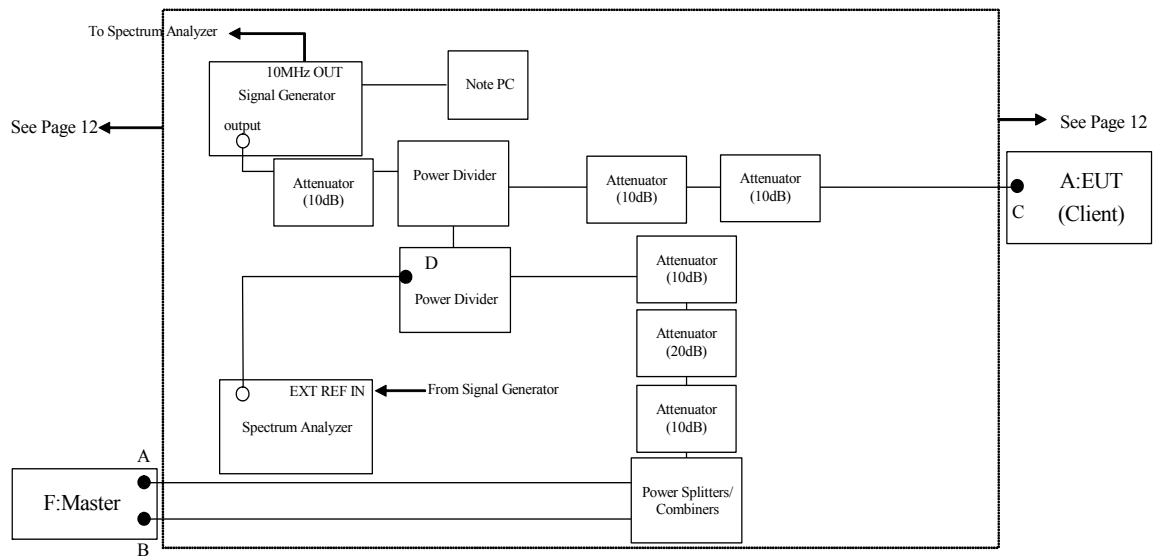
FREQUENCY HOPPING RADAR WAVEFORM GENERATING SUBSYSTEM

The first 100 frequencies are selected out of the hopping sequence of the randomized 475 hop frequencies.

Only a *Burst* that has the frequency falling within the receiver bandwidth of the tested U-NII device is selected among those frequencies. (Frequency-domain simulation). The radar waveform generated at the start time of the selected *Burst* (Time-domain simulation) is download to the Signal Generator.

If all of the randomly selected 100 frequencies do not fall within the receiver bandwidth of the U-NII device, the radar waveform is not used for the test.

CONDUCTED METHODS SYSTEM BLOCK DIAGRM



MEASUREMENT SYSTEM FREQUENCY REFERENCE

Lock the signal generator and the spectrum analyzer to the same reference sources as follows: Connect the 10 MHz OUT on the signal generator to the EXT REF IN on the spectrum analyzer and set the spectrum analyzer Ext to On.

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SYSTEM CALIBRATION

Step 1: Set the system as shown in Figure 3 of KDB905462 7.2.2.

Step 2: Adjust each attenuator to fulfill the following three conditions:

- WLAN can be communicated, and
- Rader detection threshold level is bigger than Client Device traffic level on the spectrum analyzer, and
- Master Device traffic level is not displayed on the spectrum analyzer.

Step 3: Terminate 50 ohm at B , C and D points, and connect the spectrum analyzer to the point A. (See the figure on page 14)

At the point A, adjust the signal generator and spectrum analyzer to the center frequency of the channel to be measured.

Download the applicable radar waveforms to the signal generator. Select the radar waveform, trigger a burst manually and measure the amplitude on the spectrum analyzer. Readjust the amplitude of the signal generator as required so that the peak level of the waveform is at a displayed level equal to the required or desired interference detection threshold.

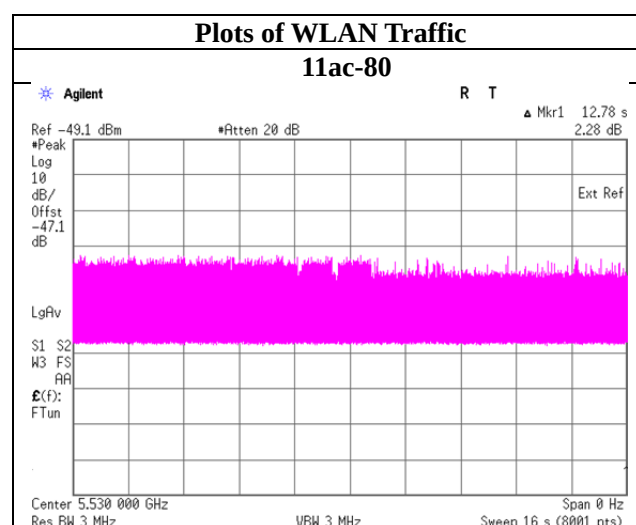
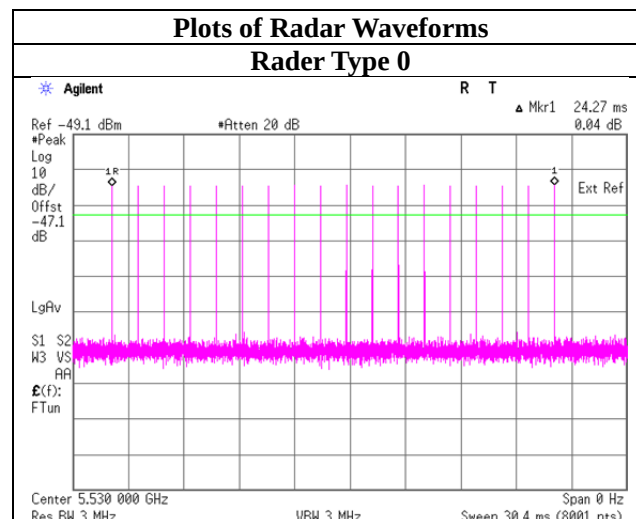
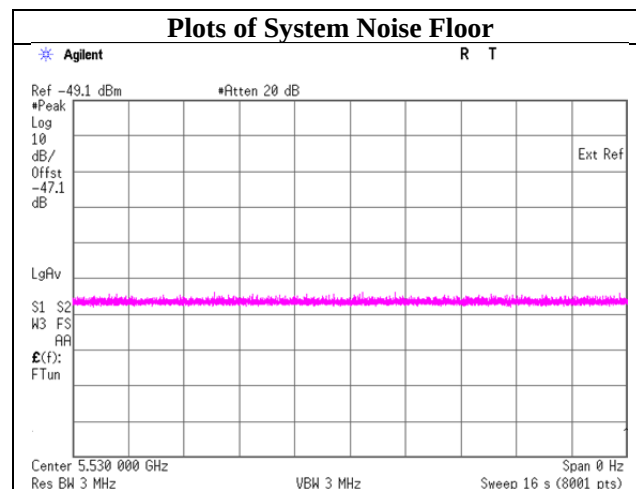
Separate signal generator amplitude settings are determined as required for each radar type.

Step 4: Without changing any of the instrument settings, restore the system setting to Step 2 and adjust the Reference Level Offset of the spectrum analyzer to the level at Step 3.

By taking the above steps 1 to 4, the spectrum analyzer displays the level of the signal generator as received at the antenna ports of the Master Device.

See Clause 5.4 for Plots of Noise, Rader Waveforms, and WLAN signals.

5.4 Plots of Noise, Rader Waveforms, and WLAN signals



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SECTION 6: Channel Move Time, Channel Closing Transmission Time

6.1 Operating environment

Test place Ise EMC Lab.No.6 Measurement Room
Date 08/30/2016
Temperature/ Humidity 23deg. C / 52% RH
Engineer Yuta Moriya
Mode 11ac-80

6.2 Test Procedure

Transmit the data from the Master Device to the Client Device on the test Channel for the entire period of the test. The Radar Waveform generator sends a Burst of pulses for one of the Short Pulse Radar Types 0 at levels defined , on the Operating Channel. An additional 1 dB is added to the radar test signal to ensure it is at or above the DFS Detection Threshold, accounting for equipment variations/errors.
Observe the transmissions of the EUT at the end of the radar Burst on the Operating Channel for duration greater than 10 seconds.

6.3 Test data

11ac-80

Test Item	Unit	Measurement Time	Limit	Results
Channel Move Time *1)	[sec]	0.076	10.000	Pass
Channel Closing Transmission Time *2)	[msec]	0	60	Pass

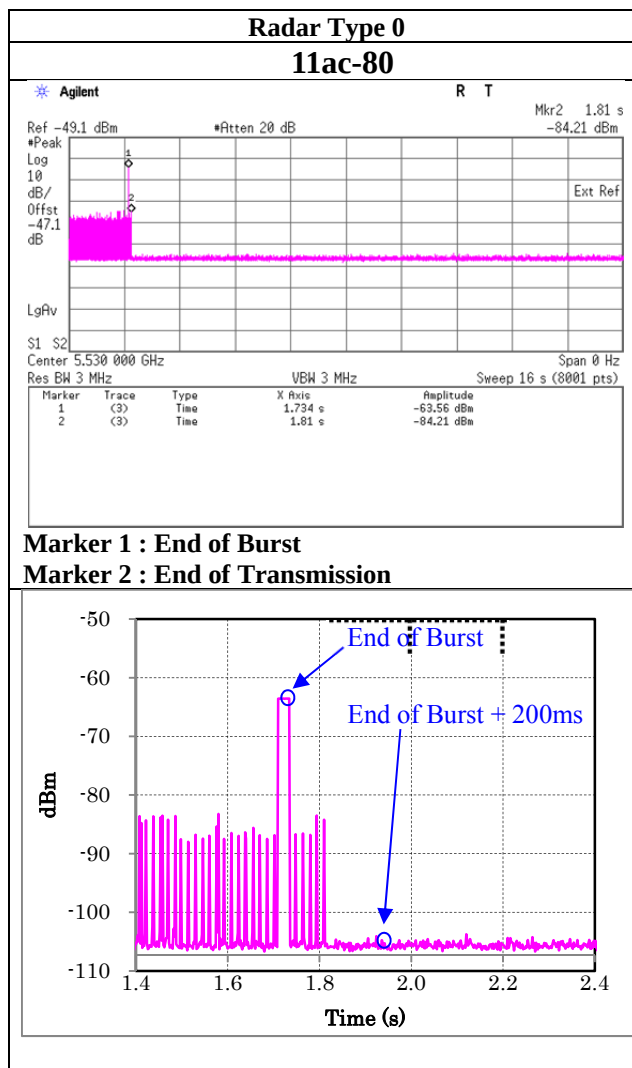
*1) Channel Move Time is calculated as follows:

(Channel Move Time) = (End of Transmission) - (End of Burst) = 1.81-1.734

*2) Channel Closing Transmission Time is calculated from (End of Burst + 200msec) to (End of Burst + 10sec)

(Channel Closing Transmission Time) = (Number of analyzer bins showing transmission) × (dwell time per bin)

= 0 × 2 [msec]



6.4 Test result

Test result: Pass

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SECTION 7: Non-Occupancy Period

7.1 Operating environment

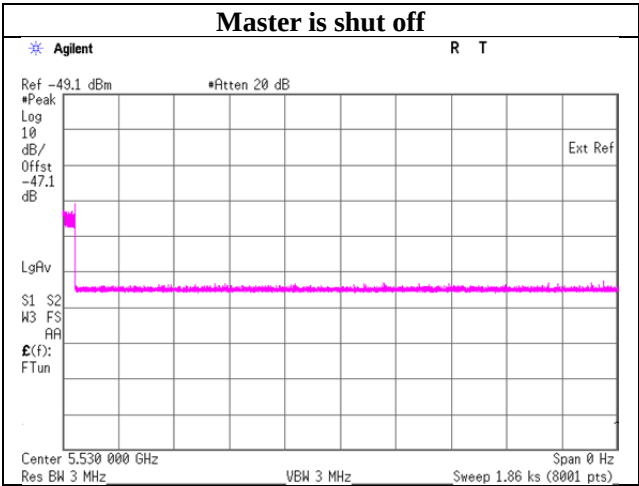
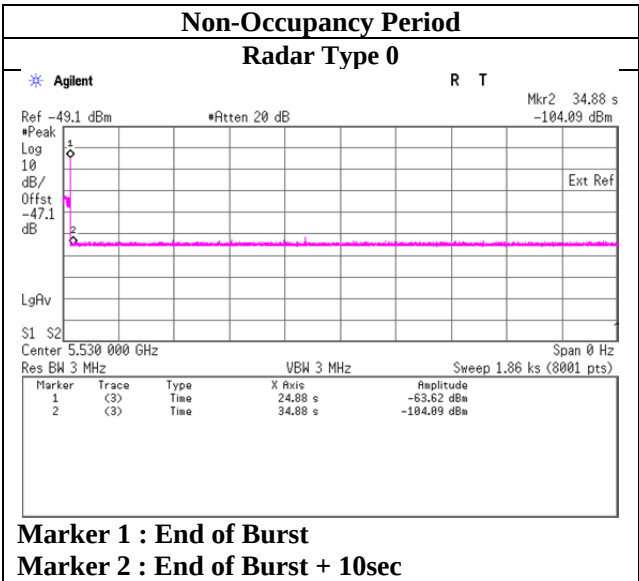
Test place	Ise EMC Lab.No.6 Measurement Room
Date	08/31/2016
Temperature/ Humidity	24deg. C / 58% RH
Engineer	Yuta Moriya
Mode	11ac-80

7.2 Test Procedure

The following two tests are performed:

- 1). Transmit the data from the Master Device to the Client Device on the test Channel for the entire period of the test. The Radar Waveform generator sends a Burst of pulses for one of the Radar Types 0 at levels defined on the Operating Channel. An additional 1 dB is added to the radar test signal to ensure it is at or above the DFS Detection Threshold, accounting for equipment variations/errors. Observe the transmissions of the EUT after the Channel Move Time on the Operating Channel for duration greater than 30 minutes.
- 2). Transmit the data from the Master Device to the Client Device on the test Channel for the entire period of the test. Observe the transmissions of the EUT on the Operating Channel for duration greater than 30 minutes after the Master Device is shut off.

7.3 Test data



7.4 Test result

Test result: Pass

APPENDIX 1: Test instruments

EMI Test Equipment

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MOS-14	Thermo-Hygrometer	Custom	CTH-201	1401	DFS	2016/01/21 * 12
MSA-13	Spectrum Analyzer	Agilent	E4440A	MY46185823	DFS	2016/06/17 * 12
EST-48	Signal Generator	Agilent	E4438C	MY45090353	DFS	2015/12/30 * 12
MCC-210	Microwave Cable	RS Components	R-132G7210200CD	-	DFS	2016/04/01 * 12
MCC-170	Microwave Cable	Junkosha	MWX221	1409S493	DFS	2016/03/11 * 12
MCC-96	Microwave Cable 1G-40GHz	Suhner	SUCOFLEX102	30817/2	DFS	2016/05/09 * 12
MCC-98	Microwave Cable 1G-40GHz	Suhner	SUCOFLEX102	30819/2	DFS	2016/05/09 * 12
MCC-67	Microwave Cable 1G-40GHz	Suhner	SUCOFLEX102	28635/2	DFS	2016/04/18 * 12
MPSC-01	Power splitters/Combiners	Mini-Circuit	ZFSC-2-2500	0124	DFS	2015/09/16 * 12
MPSC-04	Power Splitters/Combiners	Mini-Circuit	ZFSC-2-10G	0326	DFS	2015/09/18 * 12
MAT-88	Attenuator	Weinschel Associates	WA56-10	56100304	DFS	2016/06/15 * 12
MAT-89	Attenuator	Weinschel Associates	WA56-10	56100305	DFS	2016/06/09 * 12
MAT-23	Attenuator(10dB) 1-18GHz	Orient Microwave	BX10-0476-00	-	DFS	2016/03/18 * 12
MPD-01	PowerDivider DC to 26.5GHz	Agilent	11636B	52258	DFS	2016/03/23 * 12
MAT-56	Attenuator(10dB)	Suhner	6810.19.A	-	DFS	2016/01/18 * 12
MAT-60	Attenuator(20dB)	Suhner	6820.19.A	-	DFS	Pre Check
MAT-57	Attenuator(10dB)	Suhner	6810.19.A	-	DFS	2016/01/18 * 12
MTA-36	Terminator	-	50ΩSMA	-	DFS	Pre Check
MTA-44	Terminator	Mini-Circuits	ANNE-50X+	MUU3460141	DFS	Pre Check
MTA-45	Terminator	Mini-Circuits	ANNE-50X+	MUU3460142	DFS	Pre Check
COTS-MDFS-01	Signal Studio Software for DFS	Agilent	N7620A-101	5010-7739	DFS	-

*1) Signal generator is only used to generate radar test signal, and the wave form is confirmed with spectrum analyzer every time before the test.

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

DFS: Dynamic Frequency Selection

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APPENDIX 2: Photographs of test setup

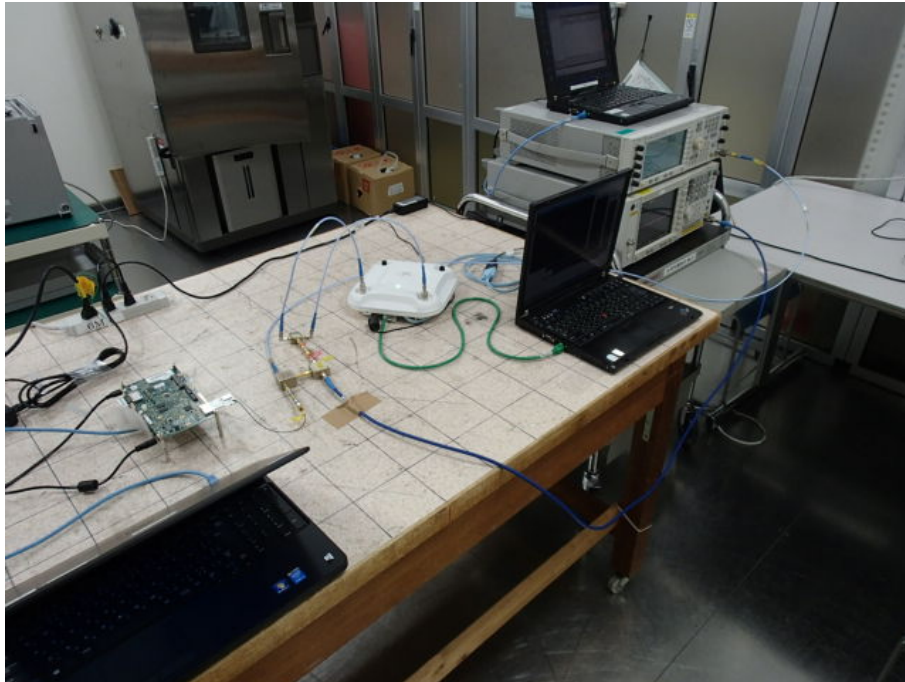


Photo 1

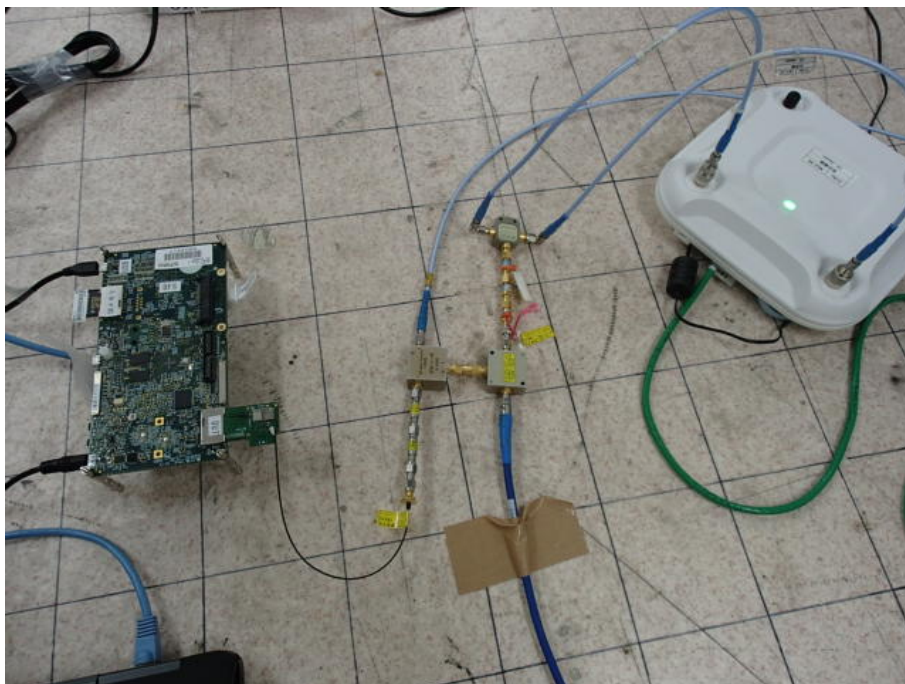


Photo 2

End of Report

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